

N-Channel JFET Monolithic Dual



SST5912

FEATURES

- High Gain $g_{fs} > 6 \text{ mS}$
- Low Leakage $I_G < 1\text{pA}$ typical
- Low Noise
- Surface Mount Package

APPLICATIONS

- Differential Wideband Amplifier
- VHF/UHF Amplifiers
- Test and Measurement

DESCRIPTION

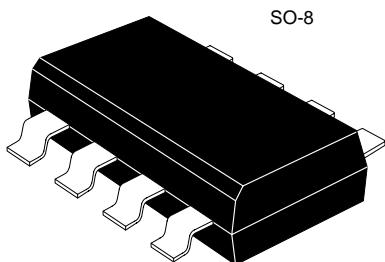
The SST5912 is a High Speed N-Channel Monolithic JFET pair encapsulated in a surface mount plastic SO-8 package. The device is designed for high gain (typically > 6000 mmhos), low leakage ($< 1\text{pA}$ typically) and low noise. The SST5912 is an excellent choice for differential wideband amplifiers, VHF/UHF amplifiers and test and measurement.

ORDERING INFORMATION

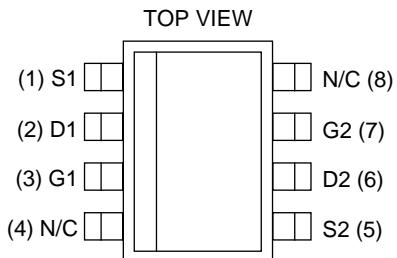
Part	Package	Temperature Range
SST5912	Plastic SO-8 Package	-55°C to +150°C

NOTE: For Sorted Chips in Carriers, See 2N5911 Series

PIN CONFIGURATION



CJ1



PRODUCT MARKING

SST5912	SST5912
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ABSOLUTE MAXIMUM RATINGS (T_A = 25°C unless otherwise noted)

Parameter/Test Condition	Symbol	Limit	Unit
Gate-Drain Voltage	V _{GD}	-25	V
Gate-Source Voltage	V _{GS}	-25	V
Forward Gate Current	I _G	50	mA
Power Dissipation (per side)	P _D	300	mW
(total)		500	mW
Power Derating (per side)		2.4	mW/ °C
(total)		4	mW/ °C
Operating Junction Temperature	T _J	-55 to 150	°C
Storage Temperature	T _{stg}	-65 to 150	°C
Lead Temperature (1/16" from case for 10 seconds)	T _L	300	°C

ELECTRICAL CHARACTERISTICS (T_A = 25°C unless otherwise noted)

SYMBOL	CHARACTERISTICS	TYP ¹	SST5912		UNIT	TEST CONDITIONS
			MIN	MAX		
STATIC						
V _{(BR)GSS}	Gate-Source Breakdown Voltage	-35	-25		V	I _G = -1mA, V _{DS} = 0V
V _{GS(OFF)}	Gate-Source Cut off Voltage	-3.5	-1	-5		V _{DS} = 10V, I _D = 1nA
I _{DSS}	Saturation Drain Current ²	15	7	40	mA	V _{DS} = 10V, V _{GS} = 0V
I _{GSS}	Gate Reverse Current	-1		-100	pA	V _{GS} = -15V, V _{DS} = 0V
		-0.2			nA	T _A = 125°C
I _G	Gate Operating Current	-1		-100	pA	V _{DG} = 10V, I _D = 5mA
		-0.2			nA	T _A = 125°C
V _{GS}	Gate-Source Voltage	-1.5	-0.3	-4	V	V _{DG} = 10V, I _D = 5mA
V _{GS(F)}	Gate-Source Forward Voltage	0.7				I _G = 1mA, V _{DS} = 0V
DYNAMIC						
g _{fs}	Common-Source Forward Transconductance	6	5	10	mS	V _{DG} = 10V, I _D = 5mA f = 1kHz
g _{os}	Common-Source Output Conductance	20		100	mS	
g _{fs}	Common-Source Forward Transconductance	6	5	10	mS	V _{DG} = 10V, I _D = 5mA f = 100MHz
g _{os}	Common-Source Output Conductance	30		150	mS	
C _{iss}	Common-Source Input Capacitance	3.5		5	pF	V _{DG} = 10V, I _D = 5mA f = 1MHz
C _{rss}	Common-Source Reverse Transfer Capacitance	1		1.2		
e _n	Equivalent Input Noise Voltage	4		20	nV/√Hz	V _{DG} = 10V, I _D = 5mA, f = 10kHz
NF	Noise Figure	0.1		1	dB	V _{DG} = 10V, I _D = 5mA, f = 10kHz, R _G = 100W
MATCHING						
V _{Gs1} - V _{Gs2}	Differential Gate Source Voltage	7		15	mV	V _{DG} = 10V, I _D = 5mA
D V _{Gs1} - V _{Gs2} DT	Gate Source Voltage Differential Change with Temperature	10		40	mV/ °C	T = -55 to 25°C
		10		40		T = 25 to 125°C
I _{DSS1} I _{DSS2}	Saturation Drain Current Ratio	0.98	0.95	1		V _{DS} = 10V, V _{GS} = 0V
g _{fs1} g _{fs2}	Transconductance Ratio	0.98	0.95	1		V _{DG} = 10V, I _D = 5mA, f = 1kHz
I _{G1} - I _{G2}	Differential Gate Current	0.01		20	nA	V _{DG} = 10V, I _D = 5mA, T _A = 125°C
CMRR	Common Mode Rejection Ratio	90			dB	V _{DD} = 5 to 10V, I _D = 5mA

NOTES: 1. For design aid only, not subject to production testing.

2. Pulse test; PW = 300ms, duty cycle ≤ 3%.